

UNISONIC TECHNOLOGIES CO., LTD

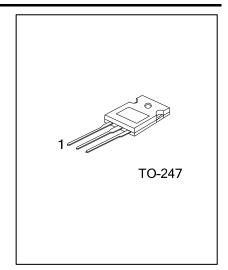
20N40 **Preliminary Power MOSFET**

400V, 23A N-CHANNEL **POWER MOSFET**

DESCRIPTION

The UTC 20N40 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

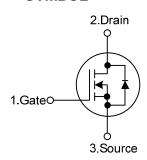
The UTC 20N40 is generally applied in high efficiency switch mode power supplies.



FEATURES

- * $R_{DS(ON)}$ =0.2 Ω @ V_{GS} =10V, I_{D} =11.5A
- * Low Gate Charge (Typical 46nC)
- * Low C_{RSS} (Typical 25pF)
- * High Switching Speed

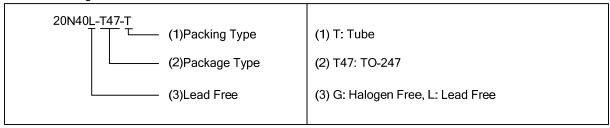
SYMBOL



ORDERING INFORMATION

Ordering Number		Deelsess	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
20N40L-T47-T	20N40G-T47-T	TO-247	G	D	S	Tube	

Pin Assignment: G: Gate D: Drain S: Source Note:



www.unisonic.com.tw 1 of 6

■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	400	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous T _C =25°C	- I _D -	23	Α
	T _C =100°C		13.8	Α
	Pulsed (Note 2)	I_{DM}	92	Α
Avalanche Current (Note 2)		I _{AR}	23	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	1190	mJ
	Repetitive (Note 2)	E_{AR}	23.5	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation (T _C =25°C)		D	235	W
Derate above 25°C		P_D	1.8	W/°C
Junction Temperature		T _J	+150	°C
Storage Temperature		T _{STG}	-55~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 4.5mH, I_{AS} = 23A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 23A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	40	°C/W	
Junction to Case	$\theta_{ m JC}$	0.53	°C/W	

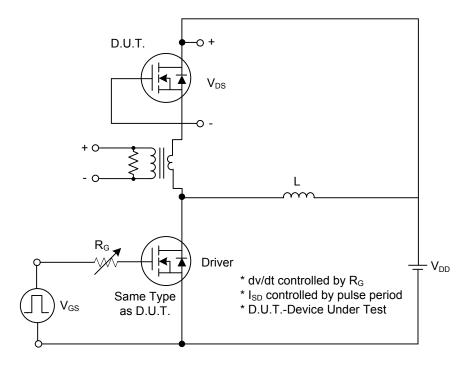
■ ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	BV _{DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	400			V		
Breakdown Voltage Temperature Coefficient	∆BV _{DSS} /∆T _J	Reference to 25°C, I _D =250µA		0.5		V/°C		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =400V, V _{GS} =0V			10	μΑ		
Gate- Source Leakage Current Forward	- 1	V_{GS} =+30V, V_{DS} =0V			+100	nA		
Reverse	I _{GSS}	V _{GS} =-30V, V _{DS} =0V			-100	nA		
ON CHARACTERISTICS	ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V		
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =11.5A		0.15	0.2	Ω		
DYNAMIC PARAMETERS	_							
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		2280	3030	pF		
Output Capacitance	Coss			370	490	pF		
Reverse Transfer Capacitance	C _{RSS}			25	38	pF		
SWITCHING PARAMETERS	_							
Total Gate Charge at 10V	$Q_{G(TOT)}$			46	60	nC		
Gate to Source Charge	Q_GS	V _{DS} =320V, I _D =23A (Note 1, 2)		13		nC		
Gate to Drain Charge	Q_GD			18		nC		
Turn-ON Delay Time	t _{D(ON)}			40	90	ns		
Rise Time	t _R	V_{DS} =200V, I_{D} =23A, R_{G} =25 Ω (Note 1, 2)		92	195	ns		
Turn-OFF Delay Time	t _{D(OFF)}			120	250	ns		
Fall-Time	t _F			75	160	ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current	Is				23	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				92	Α		
Drain-Source Diode Forward Voltage	V _{SD}	I _{SD} =23A, V _{GS} =0V			1.5	V		
Body Diode Reverse Recovery Time	t _{rr}	I _{SD} =23A, V _{GS} =0V,		110		ns		
Body Diode Reverse Recovery Charge	Q_{RR}	dI _F /dt=100A/μs (Note 1)		0.3		μC		

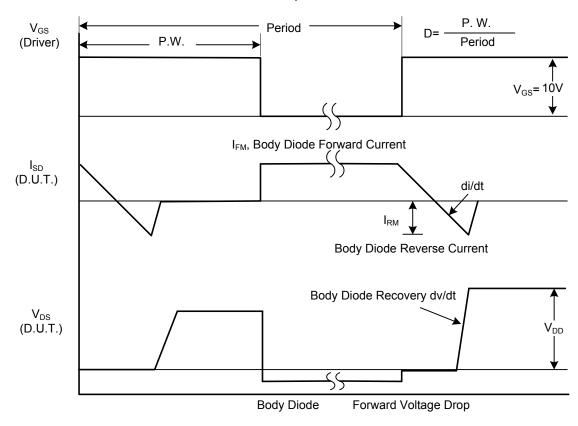
Notes: 1. Pulse Test: Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$

^{2.} Essentially Independent of Operating Temperature Typical Characteristics

■ TEST CIRCUITS AND WAVEFORMS

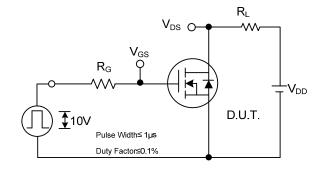


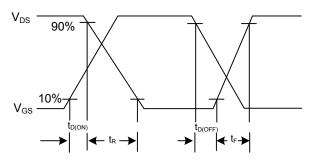
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

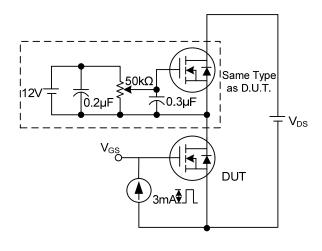
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

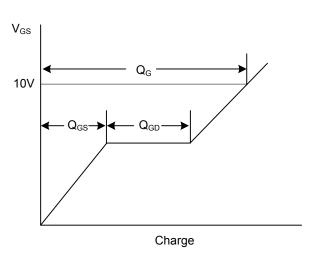




Switching Test Circuit

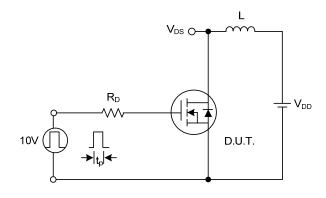
Switching Waveforms

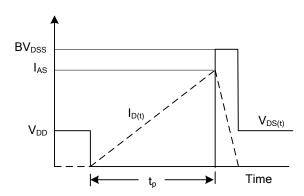




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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